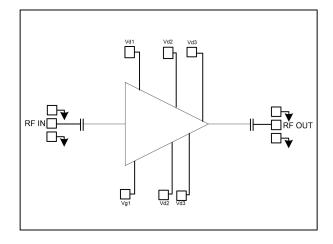


Performance characteristics

Frequency range: 15-17GHz Small Signal Gain: 26 dB Power gain: 23dB P-1dB: 34.5 dBm Psat: 35 dBm PAE: 36%~39% Power supply: +7 V / 600 mA 50Ohm input/output 100% on-chip testing Chip size : 2.75 x 1.6 x 0.1mm

Functional Block Diagram



Product Introduction:

GPA-1517-35A is a high-gain, high-efficiency, high- power amplifier chip based on GaAs technology, covering a frequency range of 15~17GHz, with a small signal gain of 26dB, a power gain of 23dB, a saturated output power of 35 dBm, and an additional efficiency of 36%~39%. The chip via metallization process ensures good grounding, and the back side is metallized, which is suitable for eutectic sintering process.

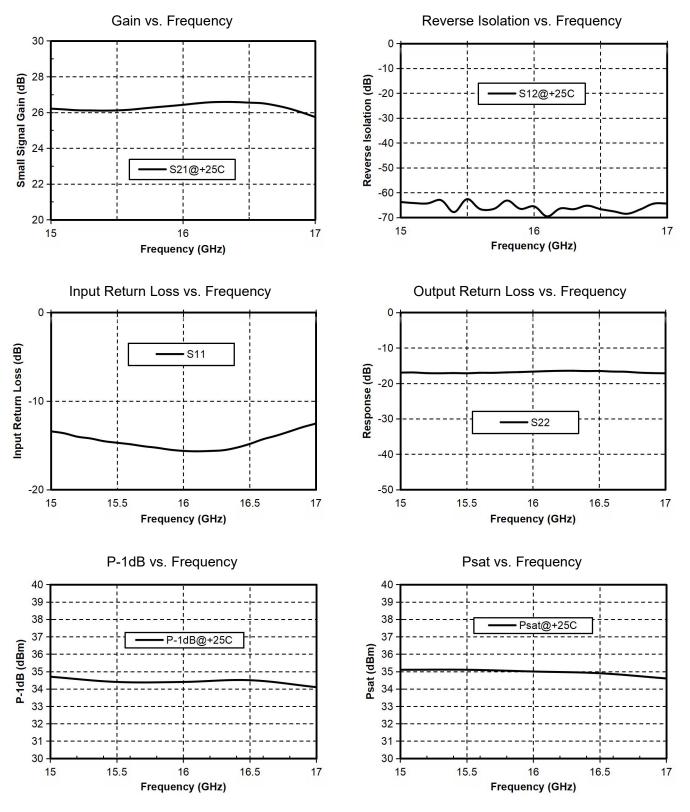
| Use restriction parameter ¹ | | | | |
|--|--------------|--|--|--|
| Maximum drain voltage | +8 V | | | |
| Maximum gate bias | - 3 V | | | |
| Maximum input power | +17 dBm | | | |
| Operating temperature | -55 ~ +85°C | | | |
| Storage temperature | -65 ~ +150°C | | | |

[1] Exceeding any of these maximum limits may cause permanent damage.

| index | Minimum | Typical Value | Maximum | unit |
|--------------------|---------|---------------|---------|------|
| Frequency Range | 15 - 17 | | | GHz |
| Small Signal Gain | 25.5 | 26 | 26.5 | dB |
| Gain Flatness | ± 0.5 | | | dB |
| P-1dB | 34 | 34.5 | 34.7 | dBm |
| Psat | 34.5 | 35 | 35 | dBm |
| Input return loss | - | 14 | - | dB |
| Output return loss | - | 16 | - | dB |

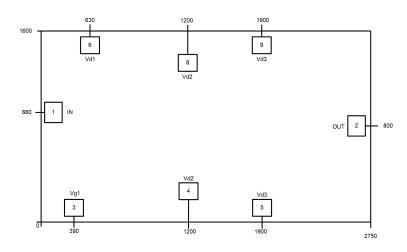


Main index test curve





Appearance structure ²

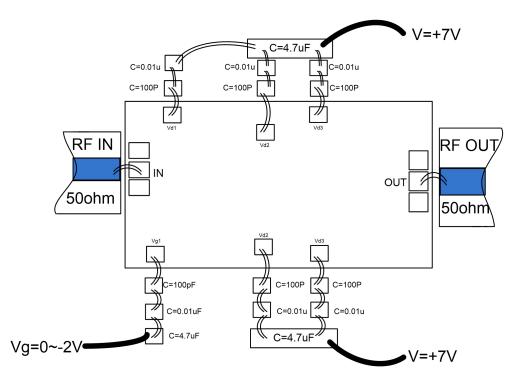


[2] All units in the figure are micrometers

| Bonding point definition | | | | |
|--------------------------|--------------------|--|--------------------|--|
| Bonding point number | Function Symbol | Functional Description | Equivalent Circuit | |
| 1 | RF IN | The signal input terminal is connected to a 50 ohm circuit, and no DC blocking capacitor is required | | |
| 2 | RF OUT | The signal output terminal is connected to a 50 ohm circuit, and no DC blocking capacitor is required | RF OUT | |
| 4, 5, 6, 8, 9 | Vd 1~4 | Amplifier drain bias, external 100pF, 0.1uf F, 4.7uF bypass capacitors are required | | |
| 3 | Vg1 | Amplifier gate bias, external 100pF, 0.1uf F, 4.7uF bypass capacitors are required | VgO | |
| Chip bottom | GND | The bottom of the chip needs to be in good contact with the RF and DC grounds | | |



Recommended assembly diagram



Notice

- The chip must be stored in an anti-static container and kept in a nitrogen environment.
- Do not attempt to clean the bare die surface using wet chemical methods.
- Please strictly follow the ESD protection requirements to avoid static damage to the bare chip.
- General operation: Please use precision pointed tweezers to pick up bare chips. Avoid touching the chip surface with tools or fingers during operation.
- Rack mounting operation suggestions: AuSn solder eutectic sintering process can be used for bare chip mounting. The mounting surface must be clean and flat.
- Sintering process: It is recommended to use AuSn solder sheets with a gold-tin ratio of 80/20. The working surface temperature reaches 255 °C and the tool (vacuum chuck) temperature reaches 265 °C. When the high-temperature mixed gas (nitrogen-hydrogen ratio of 90/10) is blown to the chip, the temperature at the top of the tool should be raised to 290 °C. Do not let the chip exceed 320 °C for more than 20 seconds. The friction time should not exceed 3 seconds.
- Bonding operation suggestions: Use Φ0.025mm (1mil) gold wire for both ball and wedge bonding. Thermosonic bonding temperature is 150 °C. The pressure of the wedge bonding knife is 40~50gf for ball bonding and 18~22gf for wedge bonding. Use the smallest possible ultrasonic energy. The bonding starts at the pressure point on the chip and ends at the package (or substrate).